Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/633,609	BRUHN ET AL.
	Examiner	Art Unit	
	Jerry Lin	1631	

SEARCHED			
Class	Subclass	Date	Examiner
702	19	9/11/2006	JL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST, Google Scholar: microarray, clevaed, probe, subarray, memory, pattern	9/11/2006	JL
Inventor Search	9/11/2006	JL